

Features

- Uses SkySilicon advanced SkyMOS2 technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria

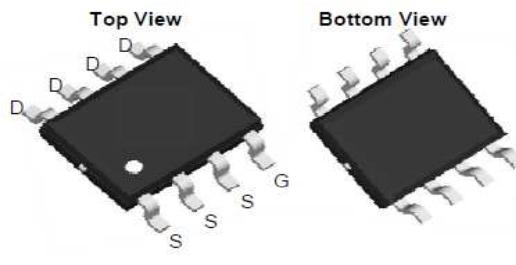
Product Summary

VDS	100V
$R_{DS(on)}$ (VGS=10V)	7mΩ
$R_{DS(on)}$ (VGS=4.5V)	8.6mΩ
I_D	13A

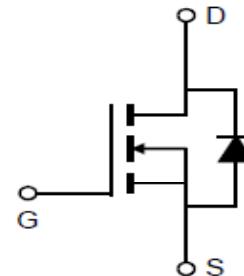
Applications

- Synchronous Rectification for AC/DC Quick Charger
- Battery management
- UPS (Uninterruptible Power Supplies)

100% Avalanche Tested



SKSE100N10NL



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
SKSE100N10NL	-	SOP-08	Tube	N/A	N/A	100pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	100	V
Continuous drain current $T_A = 25^\circ C$	I_D	13	A
$T_A = 75^\circ C$		9.5	
Pulsed drain current ($T_A = 25^\circ C$, t_p limited by T_{jmax})	$I_{D\ pulse}$	52	A
Avalanche energy, single pulse ($L=0.1mH$, $R_g=25\Omega$)	E_{AS}	-	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_A = 25^\circ C$)	P_{tot}	2.8	W
Operating junction and storage temperature	T_j, T_{stg}	-55...+150	°C

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R _{thJC}	21.8	°C/W
Thermal resistance, junction – ambient(min. footprint)	R _{thJA}	45	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	100	115	-	V	V _{GS} =0V, I _D =250μA
Gate threshold voltage	V _{GS(th)}	1.4	1.8	2.2	V	V _{DS} =V _{GS} , I _D =250μA
Zero gate voltage drain current	I _{DSS}	-	0.05	1	μA	V _{DS} =80V, V _{GS} =0V T _j =25°C T _j =125°C
Gate-source leakage current	I _{GSS}	-	10	100	nA	V _{GS} =20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	7.0	8.4	mΩ	V _{GS} =10V, I _D =13A
		-	8.6	10.5		V _{GS} =4.5V, I _D =13A
Transconductance	g _{fs}	-	32	-	S	V _{DS} =5V, I _D =13A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	3972	-	pF	V _{GS} =0V, V _{DS} =50V, f=1MHz
Output Capacitance	C _{oss}	-	712	-		
Reverse Transfer Capacitance	C _{rss}	-	11	-		
Gate Total Charge	Q _G	-	43	-	nC	V _{GS} =10V, V _{DS} =50V, I _D =50A, f=1MHz
Gate-Source charge	Q _{gs}	-	6.5	-		
Gate-Drain charge	Q _{gd}	-	7.8	-		
Turn-on delay time	t _{d(on)}	-	9	-		
Rise time	t _r	-	7	-	ns	V _{GS} =10V, V _{DD} =50V, R _{G_ext} =3.7Ω
Turn-off delay time	t _{d(off)}	-	50	-		
Fall time	t _f	-	11	-		
Gate resistance	R _G	-	1.2	-	Ω	V _{GS} =0V, V _{DS} =0V, f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V _{SD}	-	0.69	0.9	V	V _{GS} =0V, I _{SD} =50A
Body Diode Reverse Recovery Time	t _{rr}	-	27	-	ns	I _F =13.5A, dI/dt=500A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	-	113	-	nC	



Typical Performance Characteristics

Fig 1: Output Characteristics

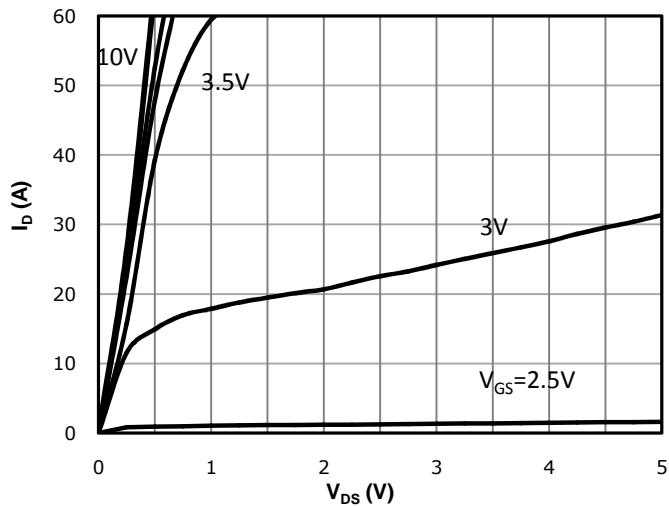


Fig 2: Transfer Characteristics

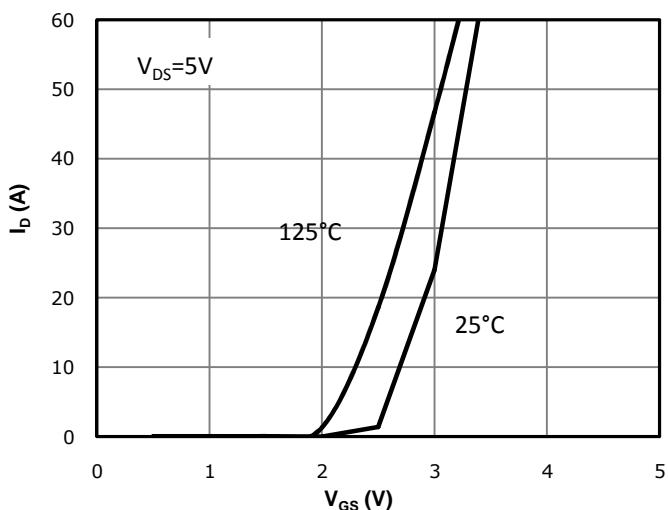


Fig 3: R_{d(on)} vs Drain Current and Gate Voltage

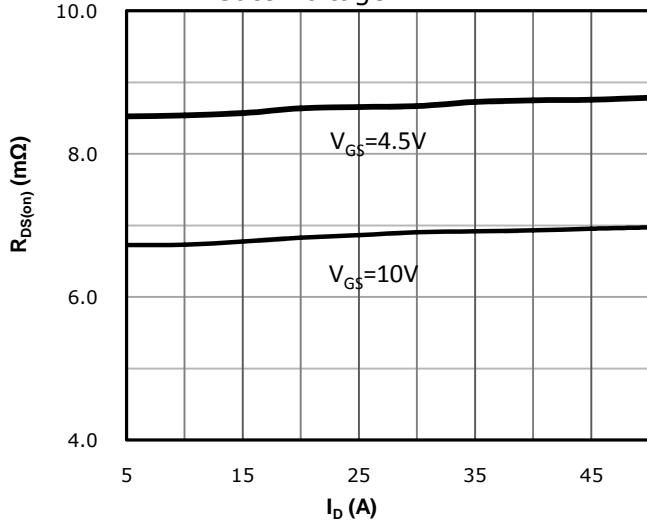


Fig 4: R_{d(on)} vs Gate Voltage

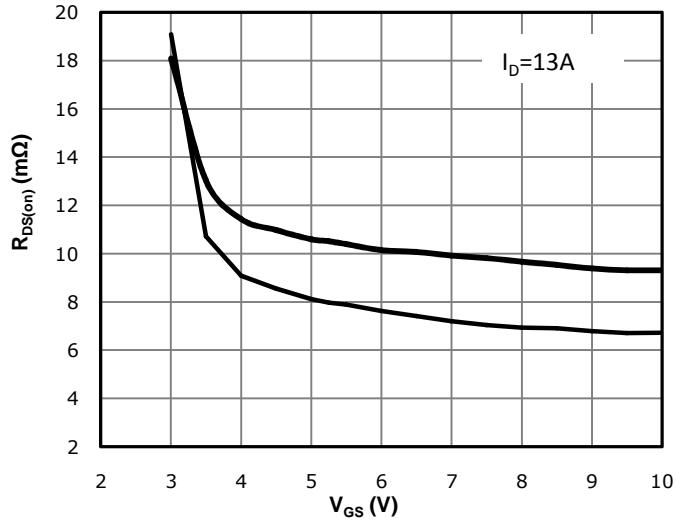


Fig 5: R_{d(on)} vs. Temperature

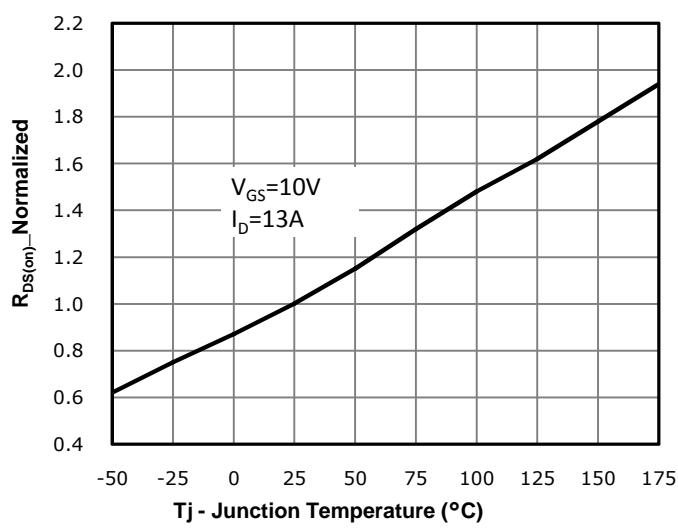


Fig 6: Capacitance Characteristics

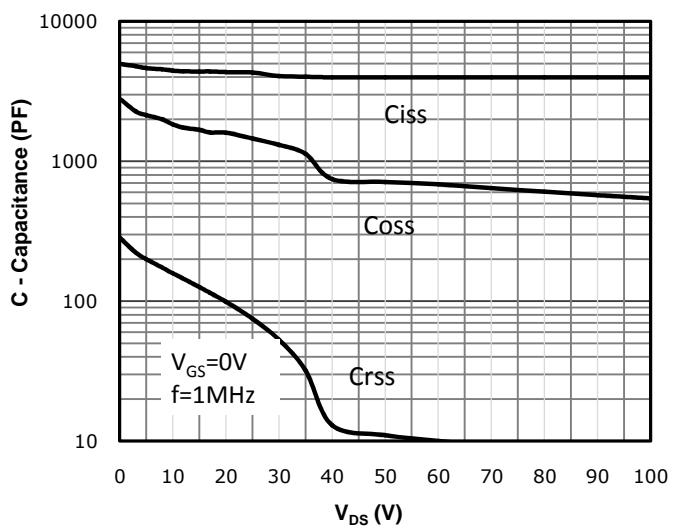


Fig 7: Gate Charge Characteristics

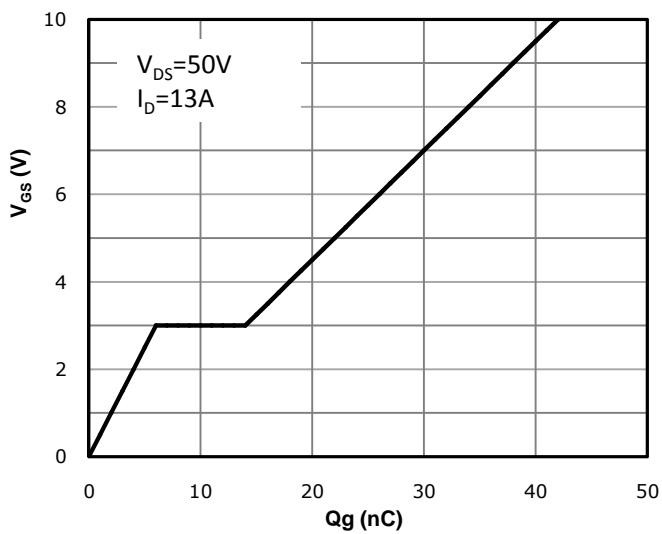


Fig 8: Body-diode Forward Characteristics

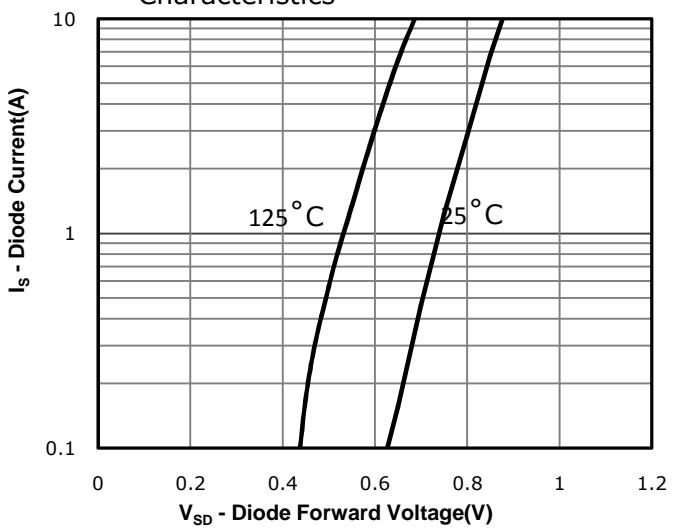


Fig 9: Power Dissipation

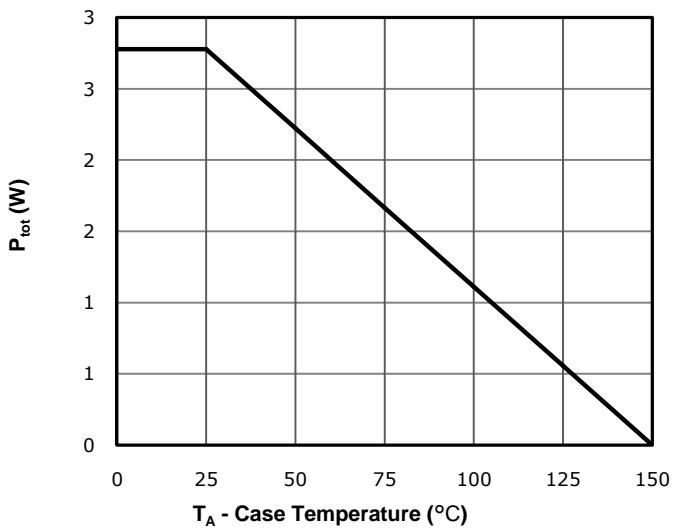
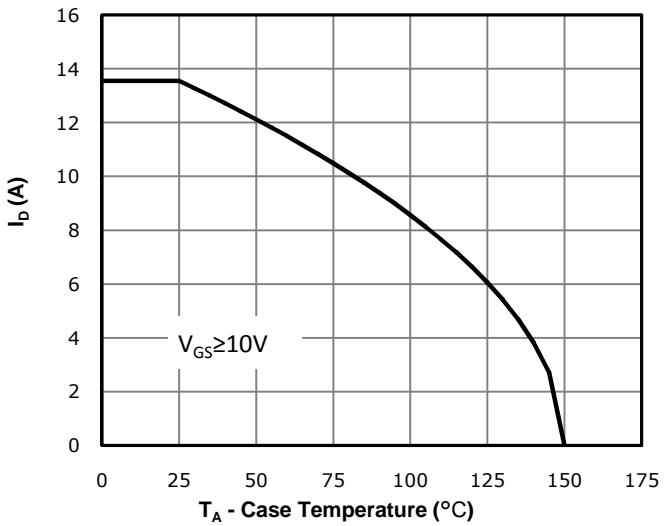
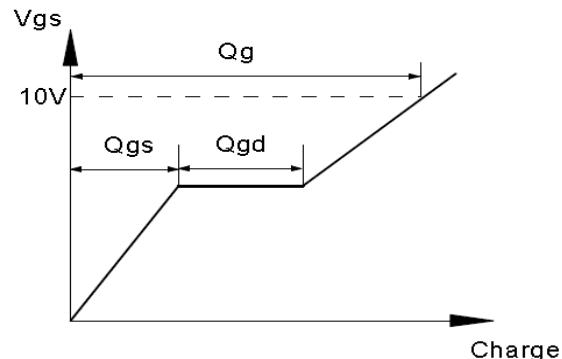
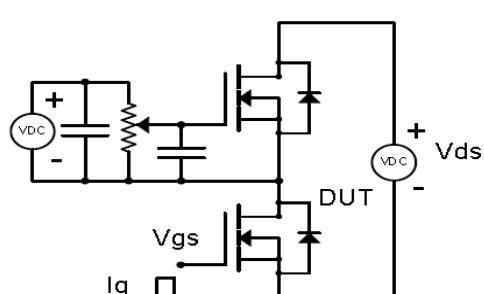


Fig 10: Drain Current Derating

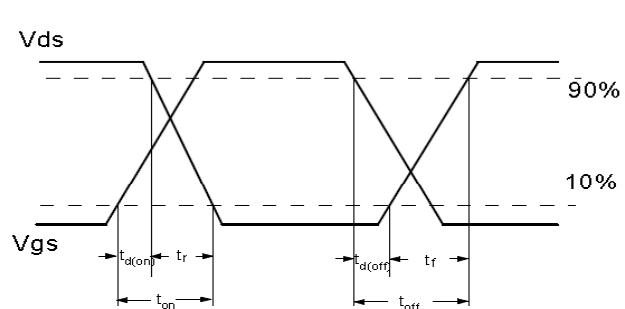
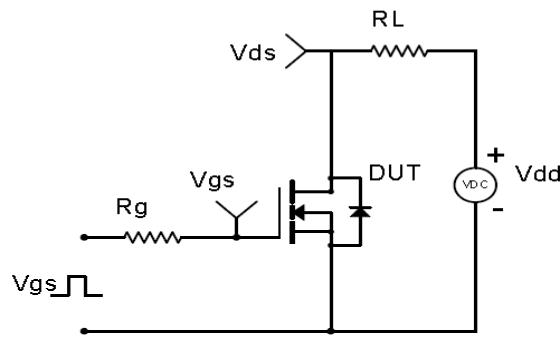


Test Circuit & Waveform

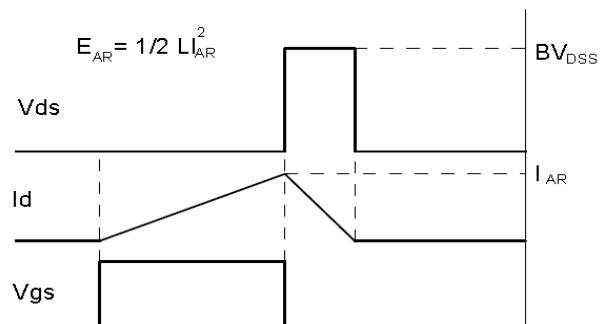
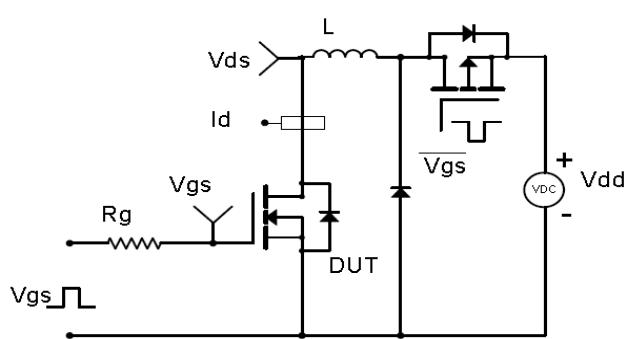
Gate Charge Test Circuit & Waveform



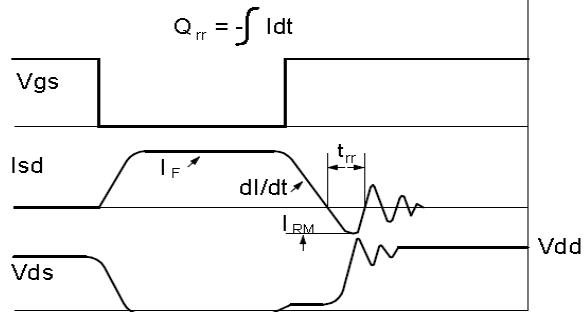
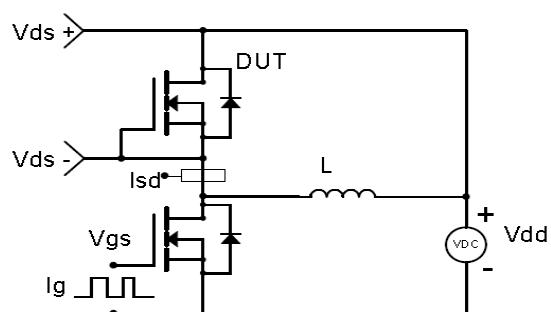
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Revision History

Revison	Date	Major changes
0.1	2017-2-18	

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

SkySilicon reserves the right to improve product design, function and reliability without notice.